



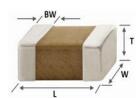


● Supplier : Samsung Electro-Mechanics ● Samsung P/N : CL10B473KB8WPNC

● AEC-Q200 Qualified

### A. Dimension

#### Dimension



Size	0603 inch		
L	1.60±0.10 mm		
W	0.80±0.10 mm		
Т	0.80±0.10 mm		
BW	0.30±0.20 mm		

# B. Samsung Part Number

<u>CL</u>	<u>10</u>	<u>B</u>	<u>473</u>	<u>K</u>	<u>B</u>	<u>8</u>	<u>W</u>	<u>P</u>	<u>N</u>	<u>C</u>
1	2	3	4	(5)	6	<b>⑦</b>	8	9	10	11

① Series	Samsung Multi-layer Ceramic Capacitor		
② Size	0603 (inch code)	L: 1.60±0.10 mm	W:0.80±0.10 mm
3 Dielectric	X7R	8 Inner electrode	Ni, Open Mode Design
④ Capacitance	<b>47</b> nF	Termination	Metal-Epoxy
⑤ Capacitance	± 10%	Plating	Sn 100% (Pb Free)
tolerance		Product	Automotive
Rated Voltage	50 V	® Special code	Normal
7 Thickness	0.80±0.10 mm	① Packaging	Cardboard Type, 7" Reel

# C. Reliability Test and Judgement condition

· · ·	Unpowered, 1,000hrs @ Max. temperature		
pacitance Change Within ±10 %	Measurement at 24±2hrs after test conclusion		
n δ : 0.03 max.			
:More than 10,000 MΩ or 500 MΩ×μF	Initial Measurement 2*		
Whichever is smaller	Final Measurement 3*		
pearance : No abnormal exterior appearance	1,000Cycles		
pacitance Change Within ±10 %	Initial Measurement 2*		
n δ : 0.03 max.	Final Measurement 3*		
: More than 10,000 № or 500 № × μF	Measurement at 24±2hrs after test conclusion		
Whichever is smaller	1 cycle condition : -55+0/-3 °C(30±3min) → Room Temp. (1min)		
	$\rightarrow$ 125+3/-0 °C (30±3min) $\rightarrow$ Room Temp. (1min)		
Defects or abnormalities	Per EIA 469		
pearance : No abnormal exterior appearance	1,000hrs 85°C/85%RH, Rated Voltage and 1.3~1.5V,		
pacitance Change Within ±12.5 %	Add 100kohm resistor		
n δ : 0.035 max.	Initial Measurement 2*		
:More than 500 MΩ or 25 MΩ×μF	Final Measurement 4*		
Whichever is smaller	Measurement at 24±2hrs after test conclusion		
	The charge/discharge current is less than 50mA.		
pearance : No abnormal exterior appearance	1,000hrs @ 125℃, 200% Rated Voltage,		
pacitance Change Within ±12.5 %	Initial Measurement 2*		
n δ :0.035 max.	Final Measurement 4*		
:More than 1,000 $^{\rm M}\!\Omega$ or 50 $^{\rm M}\!\Omega\!\times\!\mu\!F$	Measurement at 24±2hrs after test conclusion		
Whichever is smaller	The charge/discharge current is less than 50mA.		
	Whichever is smaller  Decarance: No abnormal exterior appearance Decarance Change Within ±10 %  In δ : 0.03 max.  More than 10,000 № or 500 №× μF  Whichever is smaller  Defects or abnormalities  Decarance: No abnormal exterior appearance Decarance Change Within ±12.5 %  In δ : 0.035 max.  More than 500 № or 25 №× μF  Whichever is smaller  Decarance: No abnormal exterior appearance		

	Performance	Test condition					
External Visual	No abnormal exterior appearance	Microscope ('10)					
Physical Dimension	Within the specified dimensions	Using The calipers					
Mechanical Shock	Appearance : No abnormal exterior appearance	Three shocks in each direction should be applied along					
	Capacitance Change Within ±10 %	3 mutually perpendicular axes of the test specimen (18 shocks)					
	Tan δ, IR : Initial spec.	Peak value   Duration   Wave   Velocity					
		1,500G 0.5ms Half sine 4.7m/sec					
		Initial Measurement 2*					
		Final Measurement 5*					
Vibration	Appearance : No abnormal exterior appearance	5g's for 20min., 12cycles each of 3 orientations,					
	Capacitance Change Within ±10 %	Use 8"×5" PCB 0.031" Thick 7 secure points on one long side					
	Tan δ, IR : Initial spec.	and 2 secure points at corners of opposite sides. Parts mounted					
	·	within 2" from any secure point. Test from 10~2,000Hz.					
		Initial Measurement 2*					
		Final Measurement 5*					
Resistance to	Appearance : No abnormal exterior appearance	preheating: 150°C for 60~120 sec.					
Solder Heat	Capacitance Change Within ±10 %	Solder pot : 260±5 ℃, 10±1sec.					
	Tan δ, IR : Initial spec.	Initial Measurement 2*					
		Final Measurement 3*					
ESD	Appearance : No abnormal exterior appearance	AEC-Q200-002 or ISO/DIS10605					
	Capacitance Change Within ±10 %	Initial Measurement 2*					
	Tan δ, IR : Initial spec.	Final Measurement 4*					
Solderability	95% of the terminations is to be soldered	a) Preheat at 155 °C for 4 hours, Immerse in solder for 5s at 245±5 °C					
	evenly and continuously	b) Steam aging for 8 hours, Immerse in solder for 5s at 245±5 °C					
		c) Steam aging for 8 hours, Immerse in solder for 120s at 260±5 °C					
		solder : a solution ethanol and rosin					
Electrical	Capacitance : Within specified tolerance	*A capacitor prior to measuring the capacitance is heat treated at					
Characterization	Tan δ :0.025 max.	150 +0/-10 ℃ for 1hour and maintained in ambient air for 24±2 hours					
	IR(25℃): More than 10,000 № or 500 №×μF	The Capacitance / D.F. should be measured at 25 ℃,					
	Whichever is smaller	1 kHz ± 10%, 1 ± 0.2 Vrms					
	IR(125℃) More than 1,000 № or 10 №×μF	I.R. should be measured with a DC voltage not exceeding					
	Whichever is smaller	Rated Voltage @25℃, @125℃ for 60~120 sec.					
	Dielectric Strength	Dielectric Strength : 250% of the rated voltage for 1~5 seconds					
Board Flex	Appearance : No abnormal exterior appearance	Bending to the limit, 3 mm for 60 seconds 1*					
	Capacitance Change Within ±10 %	Initial Measurement 2*					
		Final Measurement 5*					
Terminal	Appearance : No abnormal exterior appearance	10 N, for 60 sec.					
Strength(SMD)	Capacitance Change Within ±10 %	Initial Measurement 2*					
		Final Measurement 5*					
Beam Load	Destruction value should be exceed 20 N	Beam speed: 0.5±0.05 mm/sec					
Temperature	X7R						
Characteristics	From -55 $^{\circ}$ C to 125 $^{\circ}$ C, Capacitance change shou	lld be within ±15%					

### D. Recommended Soldering method :

Reflow ( Reflow Peak Temperature : 260 +0/-5°C, 30sec. ), Meet IPC/JEDEC J-STD-020 D Standard

- \*1 : The figure indicates typical specification. Please refer to individual specifications.
- \*2 : Initial measurement : Perform a heat treatment at 150 +0/-10  $^{\circ}\mathrm{C}$  for one hour after soldering process. and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
- $^{\star}3$ : Final measurement : Let sit for 24 $\pm$ 2 hours at room temperature after test conclusion, then measure.
- \*4 : Final measurement : Perform a heat treatment at 150 +0/-10 °C for one hour after soldering process. and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
- \*5 : Final measurement : Let measure within 24 hours at room temperature after test conclusion.



A Product specifications included in the specifications are effective as of March 1, 2013.

Please be advised that they are standard product specifications for reference only.

We may change, modify or discontinue the product specifications without notice at any time.

So, you need to approve the product specifications before placing an order.

Should you have any question regarding the product specifications, please contact our sales personnel or application engineers.

# Disclaimer & Limitation of Use and Application

The products listed in this Specification sheet are **NOT** designed and manufactured for any use and applications set forth below.

Please note that any misuse of the products deviating from products specifications or information provided in this Spec sheet may cause serious property damages or personal injury.

We will **NOT** be liable for any damages resulting from any misuse of the products, specifically including using the products for high reliability applications as listed below.

If you have any questions regarding this 'Limitation of Use and Application', you should first contact our sales personnel or application engineers.

- ① Aerospace/Aviation equipment
- ② Medical equipment
- 3 Military equipment
- 4 Disaster prevention/crime prevention equipment
- ⑤ Power plant control equipment
- 6 Atomic energy-related equipment
- ① Undersea equipment
- 8 Traffic signal equipment
- Data-processing equipment
- @ Electric heating apparatus, burning equipment
- Safety equipment
- @ Any other applications with the same as or similar complexity or reliability to the applications